

## SNx5HVD1176 PROFIBUS® RS-485 トランシーバ

### 1 特長

- PROFIBUS® ネットワーク向けに最適化
  - 最大 40Mbps の信号速度
  - 2.1 V を超える差動出力 (54Ω 負荷時)
  - 10pF の低バス容量 (最大値)
- TIA/EIA-485-A の要件に準拠
- ±10kV HBM を超える ESD の保護
- バスの開放、短絡、またはアイドル時のフェイル・セーフを備えるレシーバ
- バス上のトランシーバ数は最大 160 個
- 出力遷移時およびドライバのイネーブル / ディスエーブル切り替え時の低いスキュー
- 最大 50 MHz までの同相信号除去
- 回路短絡時の電流制限
- ホット・スワップに対応
- サーマル・シャットダウン保護機能

### 2 アプリケーション

- プロセス・オートメーション
  - 化学物質の製造
  - 醸造と蒸留
  - 製紙
- ファクトリ・オートメーション
  - 自動車の製造
  - ローリング、プレス、スタンプ機械
  - ネットワーク接続センサ
- 一般的な RS-485 ネットワーク
  - モータおよびモーション制御
  - HVAC およびビルディング・オートメーション・ネットワーク
  - ネットワーク接続セキュリティ・ステーション

### 3 概要

SNx5HVD1176 デバイスは、PROFIBUS (EN 50170) アプリケーションでの使用に最適化された特性を持つ、半二



重差動トランシーバです。ドライバ出力の差動電圧は、PROFIBUS の要件 (54Ω の負荷で 2.1V) を上回ります。テクノロジーの成長を、最大 40Mbps の信号速度という高いデータ転送速度で支えます。小さなバス容量により、信号の歪みが抑制されます。

SN65HVD1176 および SN75HVD1176 デバイスは、ツイストペア・ネットワークを介した差動データ転送のための ANSI 標準 TIA/EIA-485-A (RS-485) の要件を満たすか、それを上回る性能を備えています。ドライバ出力とレシーバ入力は互いに接続されており、単位負荷が 1/5 となる半二重バス・ポートを形成しているため、1 つのバスで最大 160 のノードを使用できます。バス・ラインが短絡している場合、開放されている場合、またはドライバがアクティブでない場合、レシーバの出力はロジック High に維持されます。電源電圧が 2.5V を下回ると、ドライバ出力は高インピーダンスになり、電源サイクル中またはバスへのライブ挿入中のバスの外乱を防止します。短絡フォルト状況では、内部電流制限により出力電流が一定値に制限されるので、これにより、トランシーバのバス・ピンを保護します。サーマル・シャットダウン回路は、負荷および駆動の状況に障害がある場合に発生する、過剰な消費電力による損傷からデバイスを保護します。

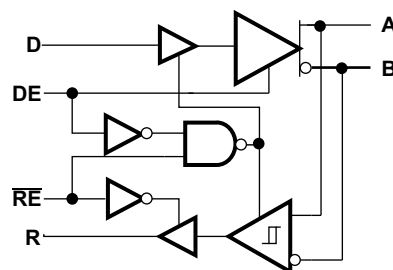
SN75HVD1176 デバイスは 0°C~70°C の温度範囲で、SN65HVD1176 デバイスは -40°C~85°C の範囲での動作が規定されています。

このデバイスの絶縁型バージョンについては、デジタル・アイソレータ内蔵の ISO1176 デバイス (SLLS897) を参照してください。

#### パッケージ情報

部品番号	パッケージ <sup>(1)</sup>	本体サイズ (公称)
SN65HVD1176 SN75HVD1176	SOIC (8)	4.90mm × 3.91mm

(1) 利用可能なパッケージについては、このデータシートの末尾にある注文情報を参照してください。



論理図 (正論理)



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## 4 Revision History

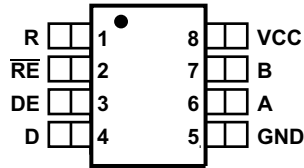
Changes from Revision H (September 2015) to Revision I (January 2023)	Page
• Changed the <i>Thermal Information</i> table .....	5
• Changed the <i>Typical Characteristics</i> graphs.....	10

Changes from Revision G (June 2015) to Revision H (September 2015)	Page
• Changed $V_{ID} \geq 0.02$ V To: $V_{ID} \geq -0.02$ V in 表 7-2 .....	17

Changes from Revision F (June 2013) to Revision G (June 2015)	Page
• 「ピン構成および機能」セクション、「ESD 定格」表、「消費電力」表、「機能説明」セクション、「デバイスの機能モード」、「アプリケーションと実装」セクション、「電源に関する推奨事項」セクション、「レイアウト」セクション、「デバイスおよびドキュメントのサポート」セクション、「メカニカル、パッケージ、および注文情報」セクションを追加.....	1
• Added storage temperature to the <i>Absolute Maximum Ratings</i> table .....	4
• Added Psi JT and Psi JB values to the <i>Thermal Information</i> table .....	5
• Deleted redundant $I_{Q(OFF)}$ and $I_{OZ}$ lines from the <i>Electrical Characteristics</i> table.....	6
• Deleted redundant $C_{OD}$ line from the <i>Electrical Characteristics</i> table.....	6

Changes from Revision E (August 2008) to Revision F (June 2013)	Page
• ピン配置とロジック図で、RE を RE に変更.....	1

## 5 Pin Configuration and Functions



☒ 5-1. D Package 8-Pin SOIC Top View

## Pin Functions

PIN		I/O	DESCRIPTION
NAME	NO.		
A	6	Bus input/output	Driver output/receiver input (complementary to B)
B	7	Bus input/output	Driver output/receiver input (complementary to A)
D	4	Digital input	Driver data input
DE	3	Digital input	Driver enable high
GND	5	Reference potential	Local device ground
R	1	Digital output	Receive data output
RE	2	Digital input	Receiver enable low
VCC	8	Supply	3-V to 5.5-V supply

## 6 Specifications

### 6.1 Absolute Maximum Ratings

over operating junction temperature range unless otherwise noted<sup>(1)</sup>

		MIN	MAX	UNIT
V <sub>CC</sub>	Supply voltage <sup>(2)</sup>	-0.5	7	V
	Voltage at any bus I/O terminal	-9	14	V
	Voltage input, transient pulse, A and B, (through 100 Ω, see <a href="#">7-15</a> )	-40	40	V
	Voltage input at any D, DE or $\overline{RE}$ terminal	-0.5	7	V
I <sub>O</sub>	Receiver output current	-10	10	mA
T <sub>J</sub>	Junction temperature		150	°C
T <sub>stg</sub>	Storage temperature	-40	130	°C

- (1) Stresses beyond those listed under *Absolute Maximum Ratings* may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under *Recommended Operating Conditions* is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability. All voltage values are with respect to the network ground terminal unless otherwise noted.
- (2) All voltage values, except differential I/O bus voltages, are with respect to network ground terminal.

### 6.2 ESD Ratings

			VALUE	UNIT
V <sub>(ESD)</sub>	Electrostatic discharge	Human body model (HBM), per ANSI/ESDA/JEDEC JS-001 <sup>(1)</sup>	±4000	V
			Bus terminals and GND	

- (1) JEDEC document JEP155 states that 500-V HBM allows safe manufacturing with a standard ESD control process.

### 6.3 Recommended Operating Conditions

			MIN	NOM	MAX	UNIT
V <sub>CC</sub>	Supply voltage		4.75	5	5.25	V
	Voltage at either bus I/O terminal	A, B	-7		12	V
V <sub>IH</sub>	High-level input voltage	D, DE, RE	2		V <sub>CC</sub>	V
V <sub>IL</sub>	Low-level input voltage		0		0.8	V
V <sub>IL</sub>	Differential input voltage	A with respect to B	-12		12	V
I <sub>O</sub>	Output current	Driver	-70		70	mA
		Receiver	-8		8	mA
T <sub>J</sub>	Junction temperature <sup>(1)</sup>	SN65HVD1176	-40		130	°C
		SN75HVD1176	0		130	°C
R <sub>L</sub>	Differential load resistance		54			Ω
1/t <sub>U1</sub>	Signaling rate				40	Mbps

(1) See the [セクション 6.7](#) table for more information on maintenance of this requirement.

### 6.4 Thermal Information

THERMAL METRIC <sup>(1)</sup>		SN75HVD1176	SN65HVD1176	UNIT
		D (SOIC)	D (SOIC)	
		8 PINS	8 PINS	
R <sub>θJA</sub>	Junction-to-ambient thermal resistance <sup>(2)</sup>	104.7	116.7	°C/W
R <sub>θJC(top)</sub>	Junction-to-case (top) thermal resistance	45.8	56.3	°C/W
R <sub>θJB</sub>	Junction-to-board thermal resistance	45.9	63.4	°C/W
ψ <sub>JT</sub>	Junction-to-top characterization parameter	5.7	8.8	°C/W
ψ <sub>JB</sub>	Junction-to-board characterization parameter	45.2	62.2	°C/W

- (1) For more information about traditional and new thermal metrics, see the *Semiconductor and IC Package Thermal Metrics* application report, [SPRA953](#).
- (2) The intent of R<sub>θJA</sub> specification is solely for a thermal performance comparison of one package to another in a standardized environment. This methodology is not meant to and will not predict the performance of a package in an application-specific environment.

## 6.5 Electrical Characteristics

over recommended operating conditions (unless otherwise noted)

PARAMETER		TEST CONDITIONS		MIN	TYP <sup>(1)</sup>	MAX	UNIT
<b>DRIVER</b>							
$V_O$	Open-circuit output voltage	A or B	No load	0		$V_{CC}$	V
$ V_{OD(SS)} $	Steady-state differential output voltage magnitude	$R_L = 54 \Omega$	See <a href="#">7-1</a>	2.1	2.9		V
		With common-mode loading, ( $V_{TEST}$ from $-7$ V to $12$ V) See <a href="#">7-2</a>		2.1	2.7		V
$\Delta V_{OD(SS)} $	Change in steady-state differential output voltage between logic states	See <a href="#">7-1</a> and <a href="#">7-6</a>		-0.2	0	0.2	V
$V_{OC(SS)}$	Steady-state common-mode output voltage	See <a href="#">7-5</a>		2	2.5	3	V
$\Delta V_{OC(SS)}$	Change in steady-state common-mode output voltage	See <a href="#">7-5</a>		-0.2	0	0.2	V
$V_{OC(PP)}$	Peak-to-peak common-mode output voltage	See <a href="#">7-5</a>			0.5		V
$V_{OD(RING)}$	Differential output voltage over and under shoot	$R_L = 54 \Omega$ , $C_L = 50$ pF See <a href="#">7-6</a>				10%	$V_{OD(PP)}$
$I_I$	Input current	D, DE		-50		50	$\mu$ A
$I_{OS(P)}$	Peak short-circuit output current	DE at $V_{CC}$ , See <a href="#">7-8</a>	$V_{OS} = -7$ V to $12$ V	-250		250	mA
$I_{OS(SS)}$	Steady-state short-circuit output current	DE at $V_{CC}$ , See <a href="#">7-8</a>	$V_{OS} > 4$ V, Output driving low	60	90	135	mA
			$V_{OS} < 1$ V, Output driving high	-135	-90	-60	mA
<b>RECEIVER</b>							
$V_{IT(+)}$	Positive-going differential input voltage threshold	See <a href="#">7-9</a>	$V_O = 2.4$ V, $I_O = -8$ mA		-80	-20	mV
$V_{IT(-)}$	Negative-going differential input voltage threshold		$V_O = 0.4$ V, $I_O = 8$ mA	-200	-120		mV
$V_{HYS}$	Hysteresis voltage ( $V_{IT+} - V_{IT-}$ )				40		mV
$V_{OH}$	High-level output voltage	$V_{ID} = 200$ mV, $I_{OH} = -8$ mA, See <a href="#">7-9</a>		4	4.6		V
$V_{OL}$	Low-level output voltage	$V_{ID} = -200$ mV, $I_{OL} = 8$ mA, See <a href="#">7-9</a>			0.2	0.4	V
$I_A, I_B$	Bus pin input current	$V_I = -7$ V to $12$ V, Other input = $0$ V	$V_{CC} = 4.75$ V to $5.25$ V	-160		200	$\mu$ A
$I_{A(OFF)}, I_{B(OFF)}$			$V_{CC} = 0$ V	-160		200	
$I_I$	Receiver enable input current	RE		-50		50	$\mu$ A
$I_{OZ}$	High-impedance - state output current	$RE = V_{CC}$		-1		1	$\mu$ A
$R_I$	Input resistance			60			k $\Omega$
$C_{ID}$	Differential input capacitance	Test input signal is a 1.5-MHz sine wave with amplitude $1 V_{PP}$ , capacitance measured across A and B			7	10	pF
$C_{MR}$	Common mode rejection	See <a href="#">7-11</a>			4		V

(1) All typical values are at  $V_{CC} = 5$  V and  $25^\circ\text{C}$ .

## 6.6 Supply Current

PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
I <sub>CC</sub> Supply Current <sup>(1)</sup>	Driver and receiver, $\overline{RE}$ at 0 V, DE at V <sub>CC</sub> , All other inputs open, no load		4	6	mA
	Driver only, $\overline{RE}$ at V <sub>CC</sub> , DE at V <sub>CC</sub> , All other inputs open, no load		3.8	6	mA
	Receiver only, $\overline{RE}$ at 0 V, DE at 0 V, All other inputs open, no load		3.6	6	mA
	Standby only, $\overline{RE}$ at V <sub>CC</sub> , DE at 0 V, All other inputs open		0.2	5	μA

(1) Over recommended operating conditions

## 6.7 Power Dissipation

over recommended operating conditions (unless otherwise noted)

PARAMETER	TEST CONDITIONS	MIN	TYP <sup>(1)</sup>	MAX	UNIT
P <sub>D</sub> Device power dissipation	R <sub>L</sub> = 54 Ω, C <sub>L</sub> = 50 pF, 0 V to 3 V, 15 MHz, 50% duty cycle square wave input, driver and receiver enabled		277	318	mW
T <sub>A</sub> Ambient air temperature	SN65HVD1176	Low-K board, no air flow, P <sub>D</sub> = 318 mW	-40	64	°C
		High-K board, no air flow, P <sub>D</sub> = 318 mW	-40	89	°C
	SN75HVD1176	Low-K board, no air flow, P <sub>D</sub> = 318 mW	0		°C
		High-K board, no air flow, P <sub>D</sub> = 318 mW	0		°C
T <sub>SD</sub> Thermal shut down junction temperature			150		°C

(1) All typical values are with V<sub>CC</sub> = 5 V and T<sub>A</sub> = 25°C.

## 6.8 Switching Characteristics

over recommended operating conditions (unless otherwise noted)

PARAMETER	TEST CONDITIONS	MIN	TYP <sup>(1)</sup>	MAX	UNIT
<b>DRIVER</b>					
t <sub>PLH</sub> Propagation delay time low-level-to-high-level output	R <sub>L</sub> = 54 Ω, C <sub>L</sub> = 50 pF, See <a href="#">7-3</a>	4	7	10	ns
t <sub>PHL</sub> Propagation delay time high-level-to-low-level output		4	7	10	ns
t <sub>sk(p)</sub> Pulse skew   t <sub>PLH</sub> - t <sub>PHL</sub>		0	2		ns
t <sub>r</sub> Differential output rise time		2	3	7.5	ns
t <sub>f</sub> Differential output fall time		2	3	7.5	ns
t <sub>t(MLH)</sub> , t <sub>t(MHL)</sub> Output transition skew	See <a href="#">7-4</a>		0.2	1	ns
t <sub>p(AZH)</sub> , t <sub>p(BZH)</sub> t <sub>p(AZL)</sub> , t <sub>p(BZL)</sub> Propagation delay time, high-impedance-to-active output	R <sub>L</sub> = 110 Ω, C <sub>L</sub> = 50 pF See <a href="#">7-7</a>		10	20	ns
t <sub>p(AHZ)</sub> , t <sub>p(BHZ)</sub> t <sub>p(ALZ)</sub> , t <sub>p(BLZ)</sub> Propagation delay time, active-to- high-impedance output			10	20	ns
t <sub>p(AZL)</sub> - t <sub>p(BZH)</sub>    t <sub>p(AZH)</sub> - t <sub>p(BZL)</sub>   Enable skew time		RE at 0 V	0.55	1.5	ns
t <sub>p(ALZ)</sub> - t <sub>p(BHZ)</sub>    t <sub>p(AHZ)</sub> - t <sub>p(BLZ)</sub>   Disable skew time				2.5	ns
t <sub>p(AZH)</sub> , t <sub>p(BZH)</sub> t <sub>p(AZL)</sub> , t <sub>p(BZL)</sub> Propagation delay time, high-impedance-to-active output (from sleep mode)		R <sub>L</sub> = 110 Ω, C <sub>L</sub> = 50 pF See <a href="#">7-7</a>		1	4
t <sub>p(AHZ)</sub> , t <sub>p(BHZ)</sub> t <sub>p(ALZ)</sub> , t <sub>p(BLZ)</sub> Propagation delay time, active-output-to high-impedance (to sleep mode)	RE at 5 V		30	50	ns

## 6.8 Switching Characteristics (continued)

over recommended operating conditions (unless otherwise noted)

PARAMETER		TEST CONDITIONS	MIN	TYP <sup>(1)</sup>	MAX	UNIT
$t_{(CFB)}$	Time from application of short-circuit to current foldback	See <a href="#">7-8</a>		0.5		$\mu\text{s}$
$t_{(TSD)}$	Time from application of short-circuit to thermal shutdown	$T_A = 25^\circ\text{C}$ , See <a href="#">7-8</a>	100			$\mu\text{s}$



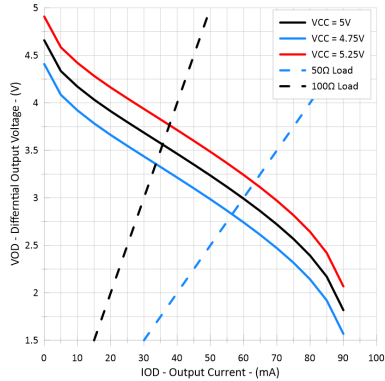
## 6.8 Switching Characteristics (continued)

over recommended operating conditions (unless otherwise noted)

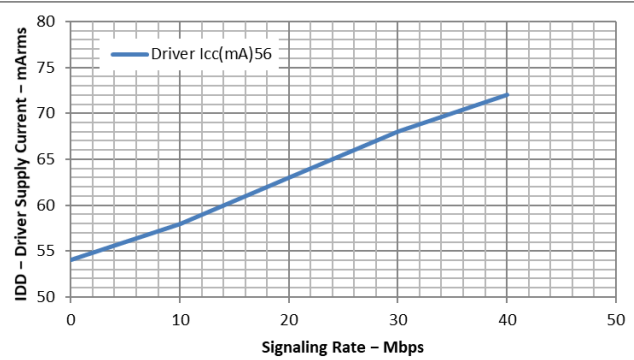
PARAMETER		TEST CONDITIONS	MIN	TYP <sup>(1)</sup>	MAX	UNIT
<b>RECEIVER</b>						
$t_{PLH}$	Propagation delay time, low-to-high level output	See <a href="#">7-10</a>	20	25		ns
$t_{PHL}$	Propagation delay time, high-to-low level output		20	25		ns
$t_{sk(p)}$	Pulse skew   $t_{PLH} - t_{PHL}$		1	2		ns
$t_r$	Receiver output voltage rise time		2	4		ns
$t_f$	Receiver output voltage fall time		2	4		ns
$t_{PZH}$	Propagation delay time, high-impedance-to-high-level output	DE at $V_{CC}$ , See <a href="#">7-13</a>			20	ns
$t_{PHZ}$	Propagation delay time, high-level-to-high-impedance output				20	ns
$t_{PZL}$	Propagation delay time, high-impedance-to-low-level output	DE at $V_{CC}$ , See <a href="#">7-14</a>			20	ns
$t_{PLZ}$	Propagation delay time, low-level-to-high-impedance output				20	ns
$t_{PZH}$	Propagation delay time, high-impedance-to-high-level output (standby to active)	DE at 0 V, See <a href="#">7-12</a>		1	4	$\mu$ s
$t_{PHZ}$	Propagation delay time, high-level-to-high-impedance output (active to standby)			13	20	ns
$t_{PZL}$	Propagation delay time, high-impedance-to-low-level output (standby to active)	DE at 0 V, See <a href="#">7-12</a>		2	4	$\mu$ s
$t_{PLZ}$	Propagation delay time, low-level-to-high-impedance output (active to standby)			13	20	ns

(1) All typical values are at  $V_{CC} = 5$  V and 25°C.

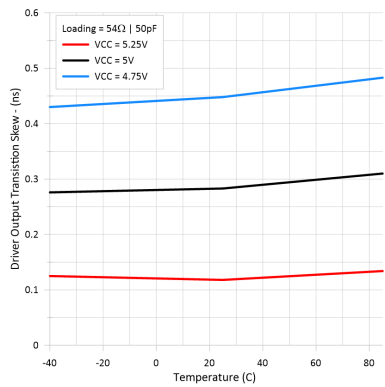
## 6.9 Typical Characteristics



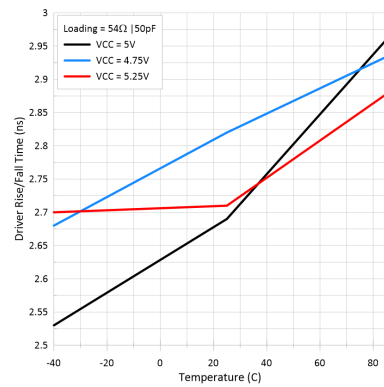
6-1. Differential Output Voltage vs Load Current



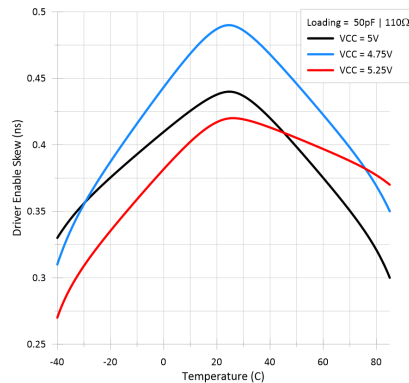
6-2. Driver Supply Current vs Signaling Rate



6-3. Driver Output Transition Skew vs Free-Air Temperature



6-4. Driver Rise, Fall Time vs Free-Air Temperature



6-5. Driver Enable Skew vs Free-Air Temperature

## Parameter Measurement Information

注

Test load capacitance includes probe and jig capacitance (unless otherwise specified).

Signal generator characteristics: rise and fall time < 6 ns, pulse rate 100 kHz, 50% duty cycle,  $Z_o = 50 \Omega$  (unless otherwise specified).

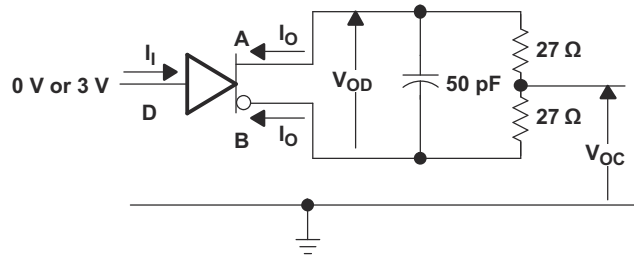


图 7-1. Driver Test Circuit,  $V_{OD}$  and  $V_{OC}$  Without Common-Mode Loading

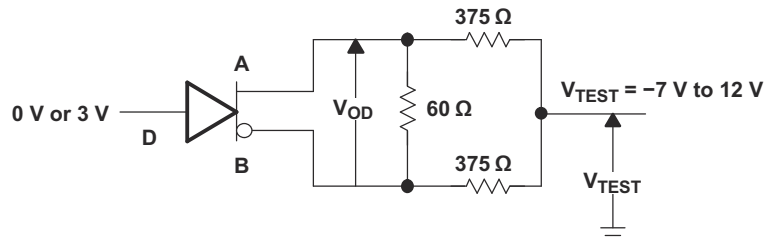


图 7-2. Driver Test Circuit,  $V_{OD}$  With Common-Mode Loading

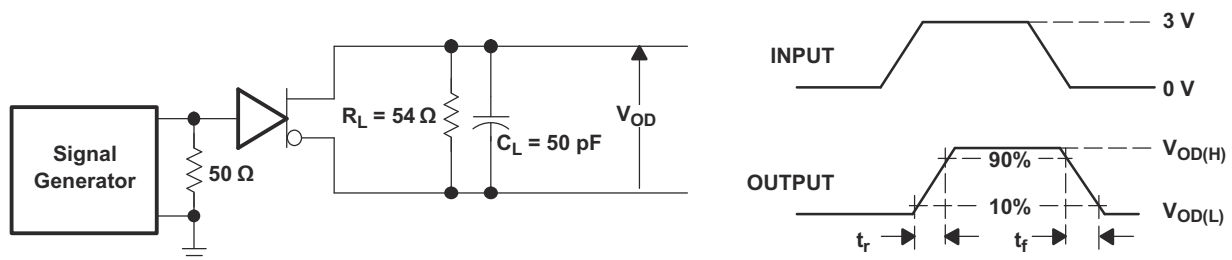
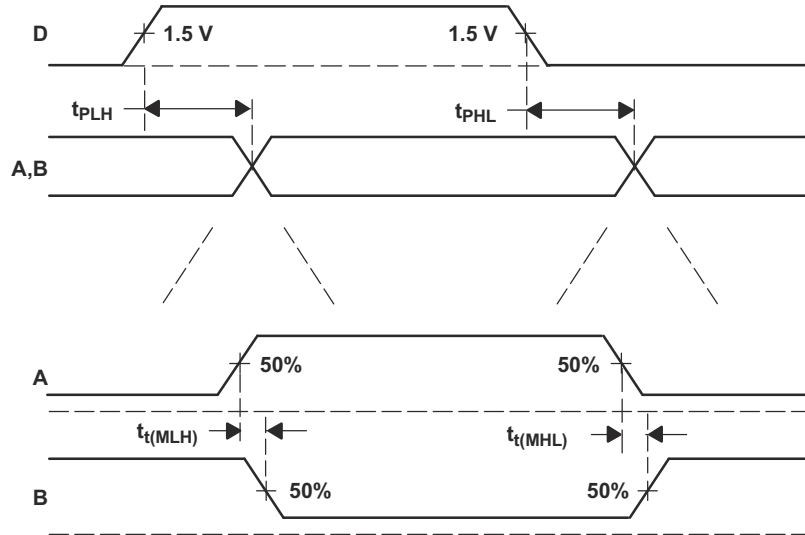
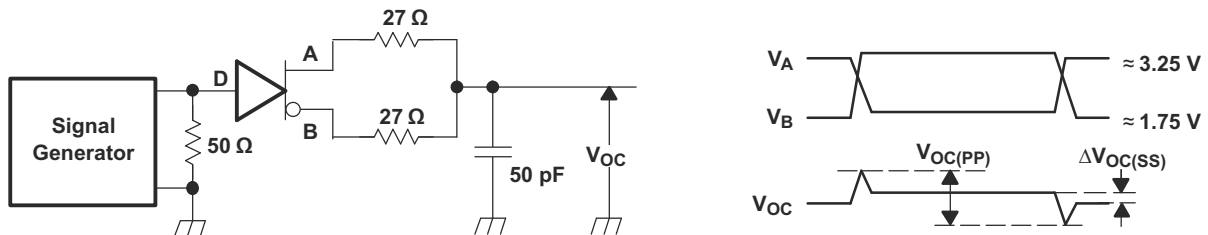


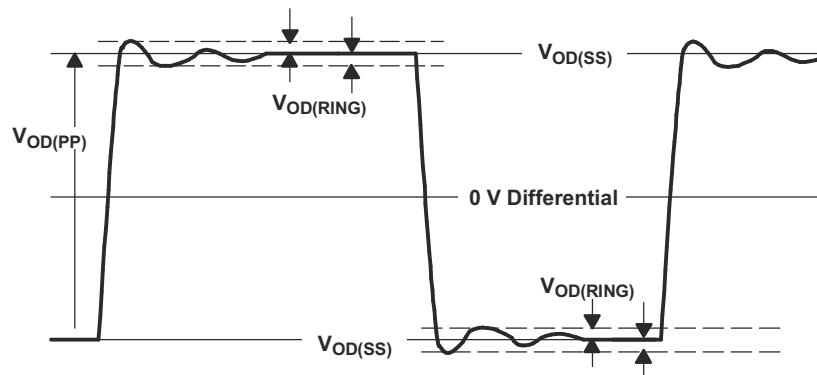
图 7-3. Driver Switching Test Circuit and Rise/Fall Time Measurement



7-4. Driver Switching Waveforms for Propagation Delay and Output Midpoint Time Measurements

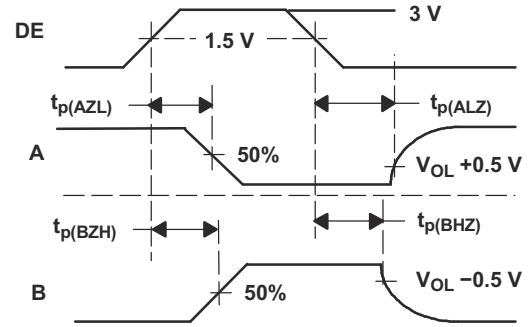
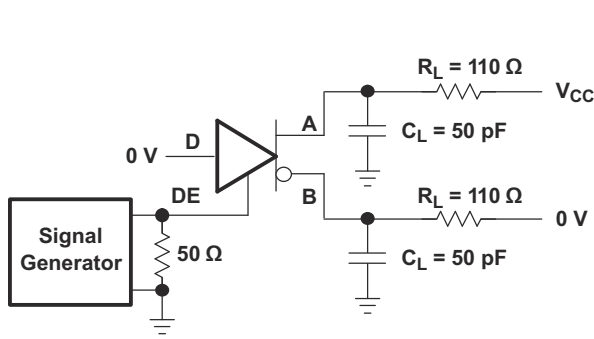


7-5. Driver  $V_{OC}$  Test Circuit and Waveforms

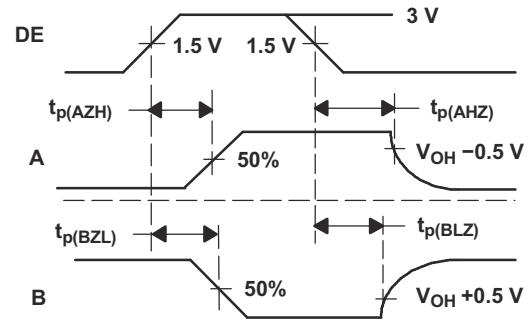
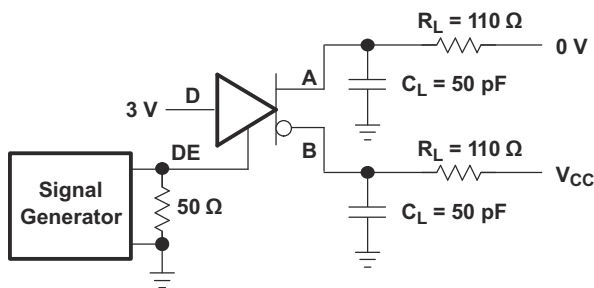


- A.  $V_{OD(RING)}$  is measured at four points on the output waveform, corresponding to overshoot and undershoot from the  $V_{OD(H)}$  and  $V_{OD(L)}$  steady state values.

7-6.  $V_{OD(RING)}$  Waveform and Definitions

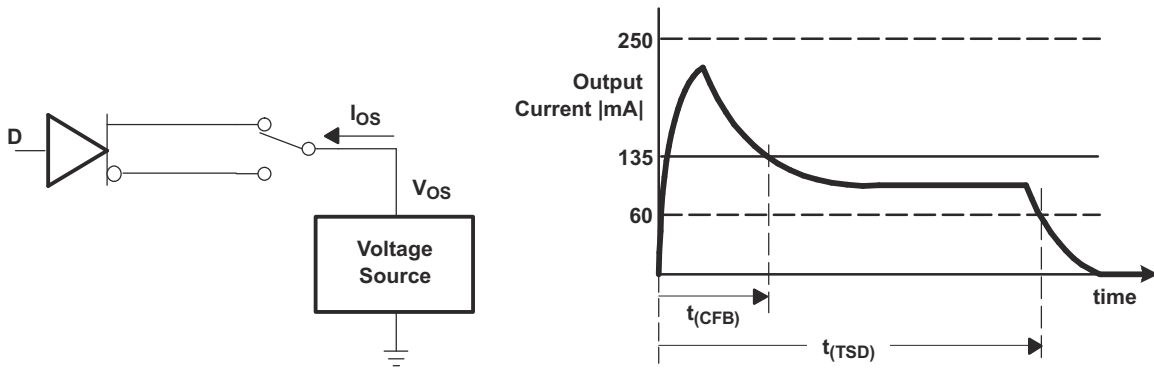


a) D at Logic Low

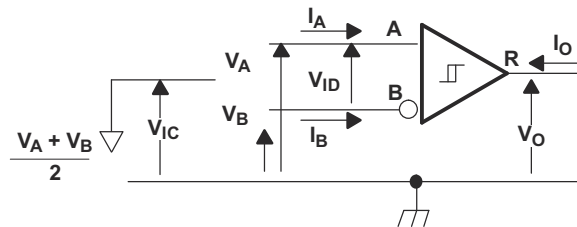


b) D at Logic High

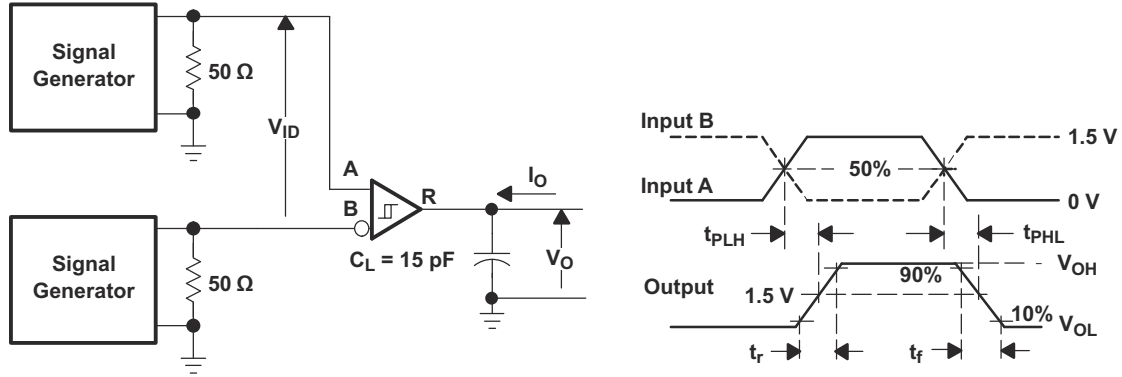
7-7. Driver Enable/Disable Test



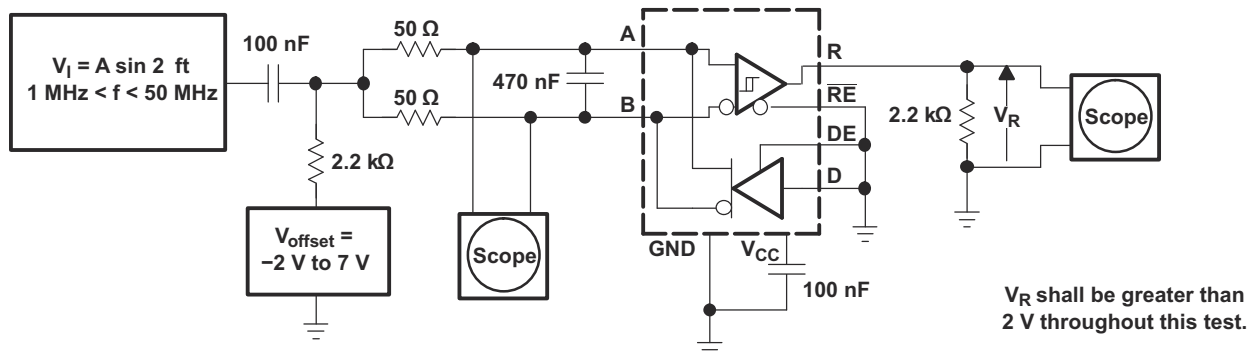
7-8. Driver Short-Circuit Test Circuit and Waveforms (Short Circuit applied at Time  $t = 0$ )



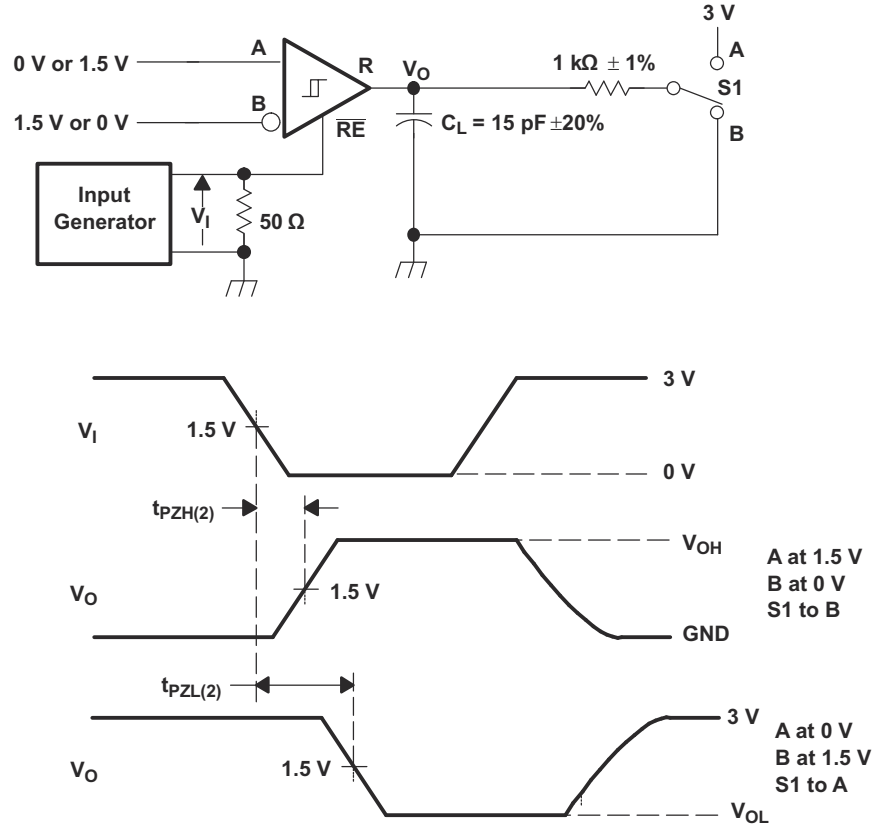
7-9. Receiver DC Parameter Definitions



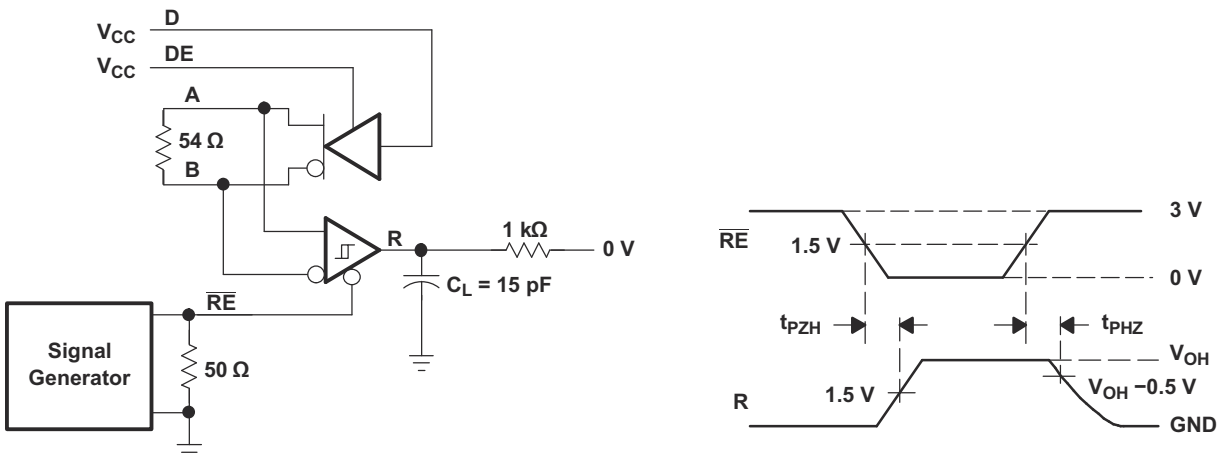
7-10. Receiver Switching Test Circuit and Waveforms



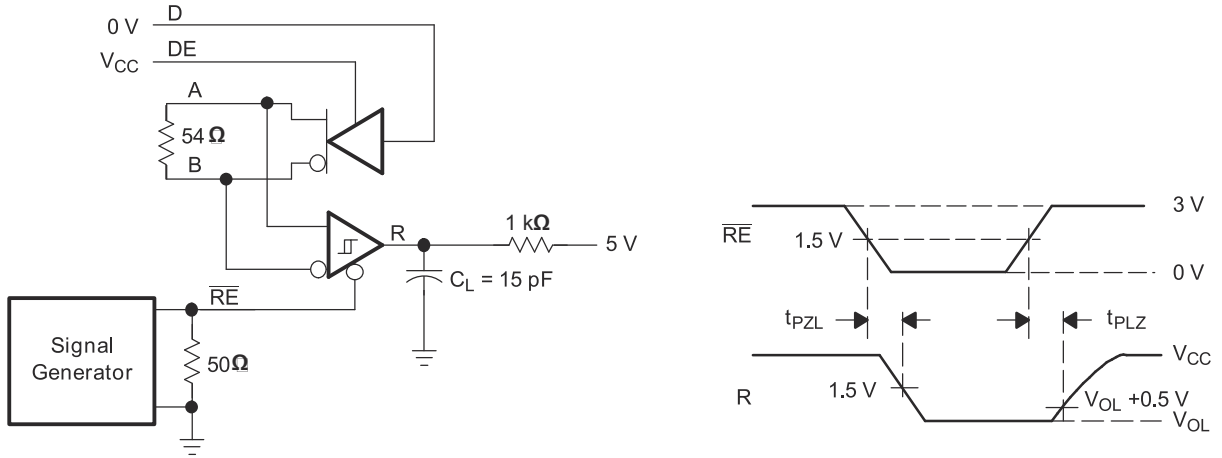
7-11. Receiver Common-Mode Rejection Test Circuit



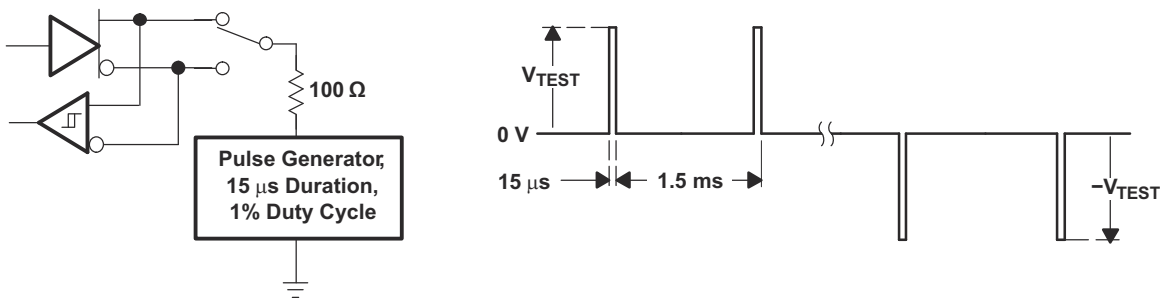
7-12. Receiver Enable Time From Standby (Driver Disabled)



7-13. Receiver Enable Test Circuit and Waveforms, Data Output High (Driver Active)



7-14. Receiver Enable Test Circuit and Waveforms, Data Output Low (Driver Active)



7-15. Test Circuit and Waveforms, Transient Overvoltage Test



## 7 Detailed Description

### 7.1 Overview

The SNx5HVD1176 device is a 5-V, half-duplex, RS-485 transceiver optimized for use in PROFIBUS (EN50170) applications and suitable for data transmission up to 40 Mbps.

The driver output differential voltage exceeds the PROFIBUS requirement of 2.1 V with a 54-Ω load, and the low transceiver output capacitance of 10 pF supports the PROFIBUS requirements for maximum bus capacitance across various data rates.

This device has an active-high driver enable and an active-low receiver enable. A standby current of less than 5 μA can be achieved by disabling both driver and receiver.

### 7.2 Functional Block Diagram

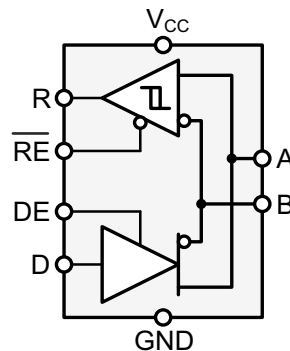


图 7-1. Logic Diagram (Positive Logic)

### 7.3 Feature Description

Internal ESD protection circuits protect the transceiver bus terminals against ±10-kV Human Body Model (HBM) electrostatic discharges and all other pins up to ±4 kV.

The SN65HVD1176 device provides internal biasing of the receiver input thresholds for open-circuit, bus-idle, or short-circuit failsafe conditions, and a typical receiver hysteresis of 40 mV.

### 7.4 Device Functional Modes

表 7-1. Driver Function Table<sup>(1)</sup>

INPUT	ENABLE	OUTPUTS	
D	DE	A	B
H	H	H	L
L	H	L	H
X	L	Z	Z
X	OPEN	Z	Z
OPEN	H	H	L

(1) H = high level, L = low level, X = don't care, Z = high impedance (off)

表 7-2. Receiver Function Table<sup>(1)</sup>

DIFFERENTIAL INPUT $V_{ID} = (V_A - V_B)$	ENABLE RE	OUTPUT R
$V_{ID} \geq -0.02$ V	L	H
$-0.2$ V < $V_{ID} < -0.02$ V	L	?
$V_{ID} \leq -0.2$ V	L	L
X	H	Z

表 7-2. Receiver Function Table<sup>(1)</sup> (continued)

DIFFERENTIAL INPUT $V_{ID} = (V_A - V_B)$	ENABLE RE	OUTPUT R
X	OPEN	Z
Open Circuit	L	H
Short Circuit	L	H
Idle (terminated) bus	L	H

(1) H = high level, L = low level, X = don't care,  
 Z = high impedance (off), ? = indeterminate

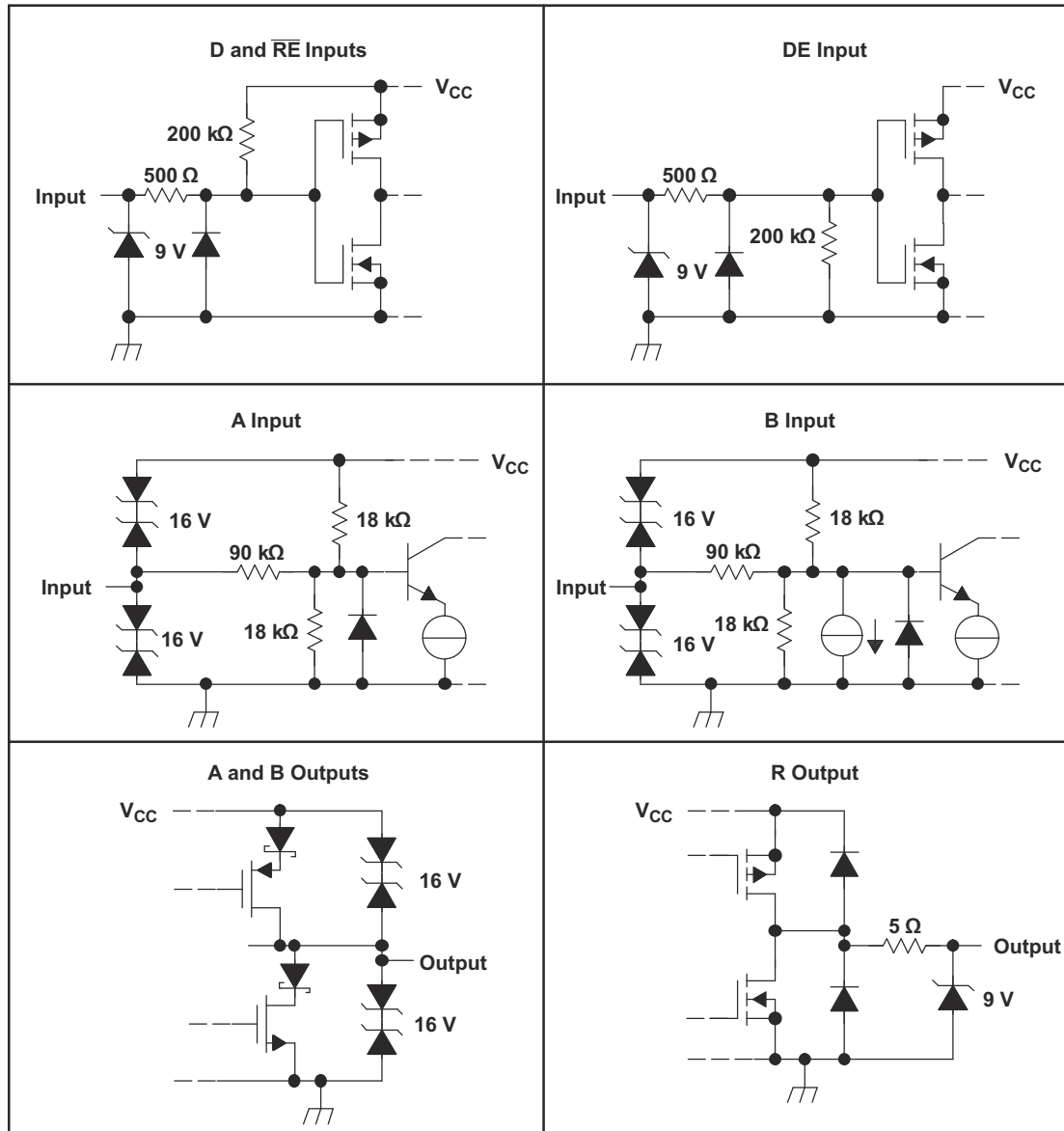


图 7-2. Equivalent Input and Output Schematic Diagrams

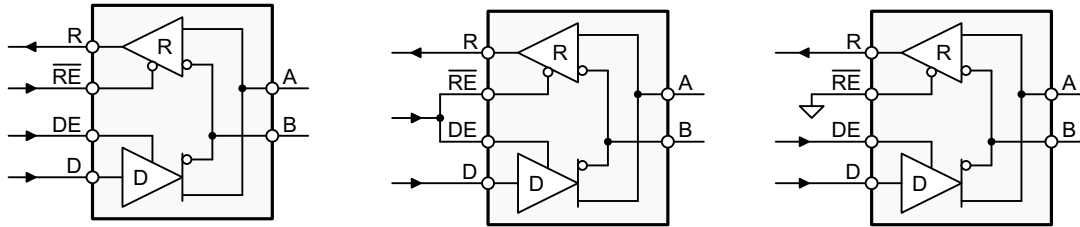
## 8 Application and Implementation

### 注

以下のアプリケーション情報は、TI の製品仕様に含まれるものではなく、TI ではその正確性または完全性を保証いたしません。個々の目的に対する製品の適合性については、お客様の責任で判断していただくこととなります。お客様は自身の設計実装を検証しテストすることで、システムの機能を確認する必要があります。

### 8.1 Application Information

The SN65HVD1176 device is a half-duplex RS-485 transceiver commonly used for asynchronous data transmissions. The driver- and receiver-enable pins allow for the configuration of different operating modes.



**図 8-1. Half-Duplex Transceiver Configurations**

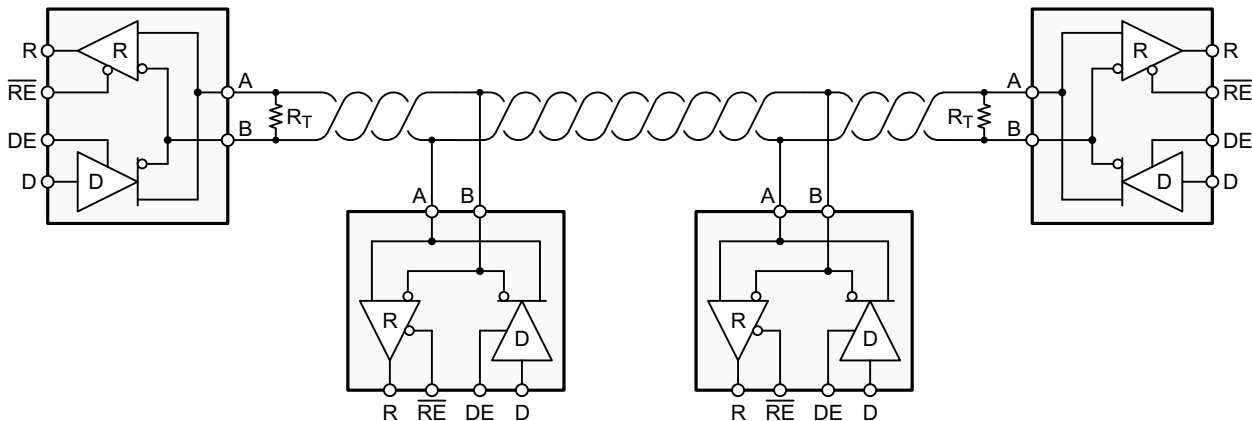
Using independent enable lines provides the most flexible control because it allows the driver and the receiver to be turned on and off individually. While this configuration requires two control lines, it allows for selective listening into the bus traffic, whether the driver is transmitting data or not.

Combining the enable signals simplifies the interface to the controller by forming a single direction-control signal. In this configuration, the transceiver operates as a driver when the direction-control line is high and as a receiver when the direction-control line is low.

Additionally, only one line is required when connecting the receiver-enable input to ground and controlling only the driver-enable input. In this configuration, a node receives the data from the bus and the data it sends; the node can also verify that the correct data has been transmitted.

### 8.2 Typical Application

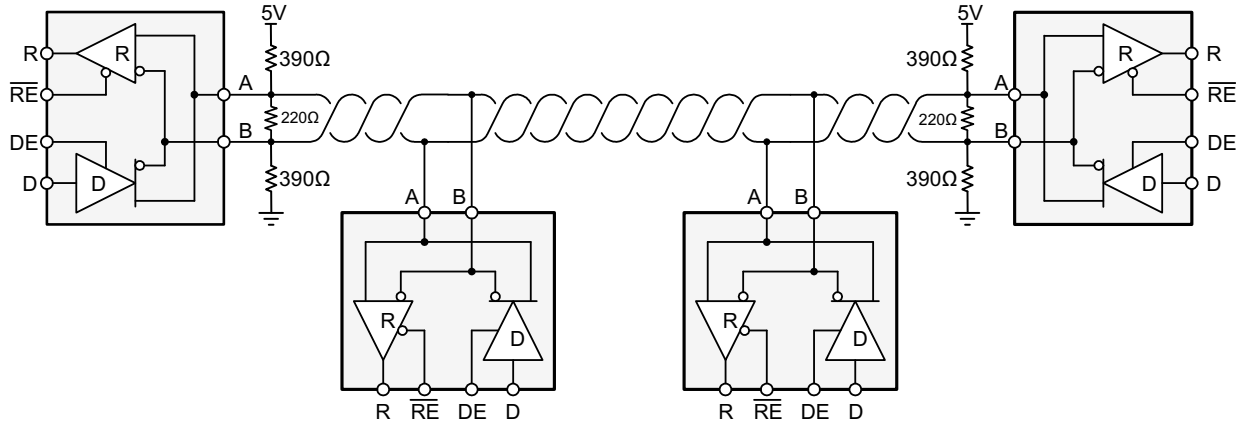
An RS-485 bus consists of multiple transceivers connecting in parallel to a bus cable. To eliminate line reflections, each cable end is terminated with a termination resistor  $R_T$  whose value matches the characteristic impedance ( $Z_0$ ) of the cable. This method, known as parallel termination, allows for higher data rates over longer cable length.



**図 8-2. Typical RS-485 Network With Half-Duplex Transceivers**

The PROFIBUS standard extends RS-485 by specifying the value of the termination resistor, the characteristic impedance of the bus cable, and the value of fail-safe termination at both ends of the bus.

PROFIBUS requires that 220-Ω termination resistors be placed at both ends of the bus, the bus cable impedance be between 135 Ω and 165 Ω, and that 390-Ω fail-safe resistors be placed on both the A and B lines at both ends of the bus.



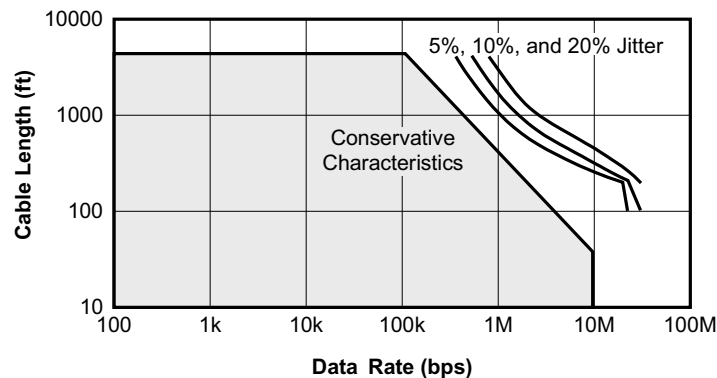
**8-3. Typical PROFIBUS network**

### 8.2.1 Design Requirements

RS-485 is a robust electrical standard suitable for long-distance networking that may be used in a wide range of applications with varying requirements, such as distance, data rate, and number of nodes.

#### 8.2.1.1 Data Rate and Bus Length

There is an inverse relationship between data rate and bus length, that is, the higher the data rate, the shorter the cable length. Conversely, the lower the data rate, the longer the cable may be without introducing data errors. While most RS-485 systems use data rates between 10 kbps and 100 kbps, some applications require data rates up to 250 kbps at distances of 4000 feet and longer. Longer distances are possible by allowing for small signal jitter of up to 5 or 10%.



**8-4. Cable Length vs Data Rate Characteristic**

### 8.2.1.2 Stub Length

When connecting a node to the bus, the distance between the transceiver inputs and the cable trunk, known as the stub, should be as short as possible. Stubs present a nonterminated piece of bus line which can introduce reflections as the length of the stub increases. As a general guideline, the electrical length, or round-trip delay, of a stub should be less than one-tenth of the rise time of the driver, thus giving a maximum physical stub length as shown in 式 1.

$$L_{\text{stub}} \leq 0.1 \times t_r \times v \times c \quad (1)$$

where:

$t_r$  is the 10/90 rise time of the driver

$c$  is the speed of light ( $3 \times 10^8$  m/s)

$v$  is the signal velocity of the cable or trace as a factor of  $c$

Per 式 1, the maximum recommended stub length for the minimum driver output rise time of the SN65HVD1176 device for a signal velocity of 78% is 0.05 meters (0.16 feet).

### 8.2.1.3 Bus Loading

The RS-485 standard specifies that a compliant driver must be able to driver 32 unit loads (UL), where 1 unit load represents a load impedance of approximately 12 k $\Omega$ . Because the SN65HVD1176 device is a 1/5 UL transceiver, it is possible to connect up to 160 receivers to the bus.

### 8.2.1.4 Receiver Failsafe

The differential receiver of the SN65HVD1176 device is *failsafe* to invalid bus states caused by the following:

- Open bus conditions, such as a disconnected connector
- Shorted bus conditions, such as cable damage shorting the twisted-pair together
- Idle bus conditions that occur when no driver on the bus is actively driving

In any of these cases, the differential receiver will output a failsafe logic-high state so that the output of the receiver is not indeterminate.

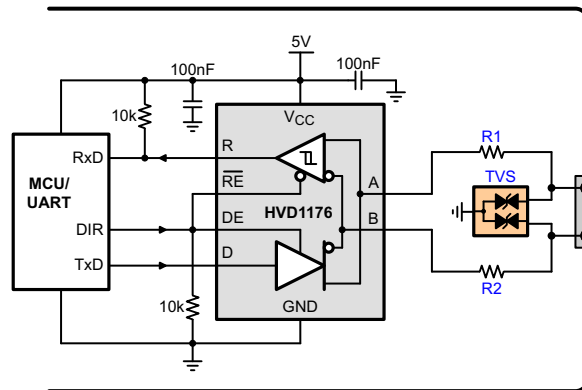
Receiver failsafe is accomplished by offsetting the receiver thresholds such that the input-indeterminate range does not include zero volts differential.

To comply with the RS-422 and RS-485 standards, the receiver output must output a high when the differential input  $V_{ID}$  is more positive than +200 mV, and must output a low when  $V_{ID}$  is more negative than –200 mV. The receiver parameters that determine the fail-safe performance are  $V_{IT(+)}$  and  $V_{IT(-)}$ .

As shown in セクション 6.5, differential signals more negative than –200 mV will always cause a low receiver output, and differential signals more positive than –20 mV will always cause a high receiver output. Thus, when the differential input signal is close to zero, it is still above the maximum  $V_{IT(+)}$  threshold of –20 mV, and the receiver output will be high.

### 8.2.2 Detailed Design Procedure

To protect bus nodes against high-energy transients, the implementation of external transient protection devices is necessary.



**图 8-5. Transient Protection Against ESD, EFT, and Surge Transients**

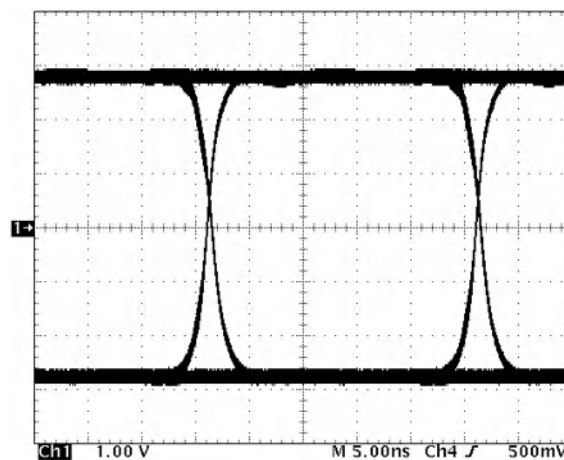
图 8-5 shows a protection circuit against 10-kV ESD (IEC 61000-4-2), 4-kV EFT (IEC 61000-4-4), and 1-kV surge (IEC 61000-4-5) transients. 表 8-1 lists the associated Bill of Materials.

**表 8-1. Bill of Materials**

Device	Function	Order Number	Manufacturer
XCVR	5-V, 40-Mbps ProfiBus Transceiver	SN65HVD1176	TI
R1, R2	10-Ω, Pulse-Proof Thick-Film Resistor	CRCW0603010RJNEAHP	Vishay
TVS	Bidirectional 400-W Transient Suppressor	CDSOT23-SM712	Bourns

### 8.2.3 Application Curve

图 8-6 demonstrates operation of the SN65HVD1179 at a signaling rate of 40 Mbps.



**图 8-6. Differential Output of SN65HVD1176 Operation at 40 Mbps**

## 9 Power Supply Recommendations

To ensure reliable operation at all data rates and supply voltages, each supply must be buffered with a 100-nF ceramic capacitor located as close to the supply pins as possible. The TPS76350 device is a linear voltage regulator suitable for the 5-V supply.

## 10 Layout

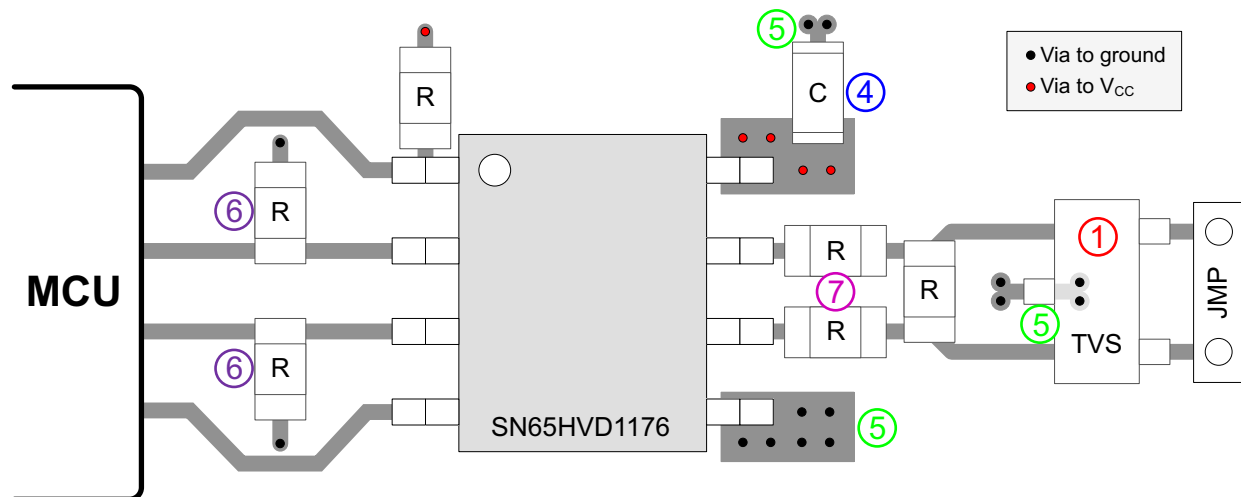
### 10.1 Layout Guidelines

On-chip IEC-ESD protection is sufficient for laboratory and portable equipment but insufficient for EFT and surge transients occurring in industrial environments. Therefore, robust and reliable bus-node design requires the use of external transient protection devices.

Because ESD and EFT transients have a wide frequency bandwidth from approximately 3 MHz to 3 GHz, high frequency layout techniques must be applied during PCB design.

1. Place the protection circuitry close to the bus connector to prevent noise transients from entering the board.
2. Use VCC and ground planes to provide low-inductance.
3. Design the protection components into the direction of the signal path. Do not force the transient currents to divert from the signal path to reach the protection device.
4. Apply 100-nF to 220-nF bypass capacitors as close as possible to the VCC pins of the transceiver, the UART, or the controller ICs on the board.
5. Use at least two vias for VCC and ground connections of bypass capacitors and protection devices to minimize effective via inductance.
6. Use 1-k $\Omega$  to 10-k $\Omega$  pullup and pulldown resistors for enable lines to limit noise currents in these lines during transient events.
7. Insert series pulse-proof resistors into the A and B bus lines if the TVS clamping voltage is higher than the specified maximum voltage of the transceiver bus terminals. These resistors limit the residual clamping current into the transceiver and prevent it from latching up.
8. While pure TVS protection is sufficient for surge transients up to 1 kV, higher transients require metal-oxide varistors (MOVs) that reduce the transients to a few hundred volts of clamping voltage and transient blocking units (TBUs) that limit transient current to less than 1 mA.

### 10.2 Layout Example



**10-1. SNx5HVD08 Layout Example**

## 11 Device and Documentation Support

### 11.1 サード・パーティ製品に関する免責事項

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### 11.2 Documentation Support

For related documentation see the following: *ISO1176 ISOLATED RS-485 PROFIBUS TRANSCEIVER (SLLS897)*

### 11.3 Related Links

The table below lists quick access links. Categories include technical documents, support and community resources, tools and software, and quick access to sample or buy.

表 11-1. Related Links

PARTS	PRODUCT FOLDER	SAMPLE & BUY	TECHNICAL DOCUMENTS	TOOLS & SOFTWARE	SUPPORT & COMMUNITY
SN65HVD1176	<a href="#">Click here</a>	<a href="#">Click here</a>	<a href="#">Click here</a>	<a href="#">Click here</a>	<a href="#">Click here</a>
SN75HVD1176	<a href="#">Click here</a>	<a href="#">Click here</a>	<a href="#">Click here</a>	<a href="#">Click here</a>	<a href="#">Click here</a>

### 11.4 サポート・リソース

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### 11.7 用語集

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## 12 Mechanical, Packaging, and Orderable Information

The following pages include mechanical, packaging, and orderable information. This information is the most current data available for the designated devices. This data is subject to change without notice and revision of this document. For browser-based versions of this data sheet, refer to the left-hand navigation.



**PACKAGING INFORMATION**

Orderable Device	Status (1)	Package Type	Package Drawing	Pins	Package Qty	Eco Plan (2)	Lead finish/ Ball material (6)	MSL Peak Temp (3)	Op Temp (°C)	Device Marking (4/5)	Samples
SN65HVD1176D	OBSOLETE	SOIC	D	8		TBD	Call TI	Call TI	-40 to 85	VP1176	
SN65HVD1176DR	ACTIVE	SOIC	D	8	2500	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 85	VP1176	Samples
SN65HVD1176DRG4	ACTIVE	SOIC	D	8	2500	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 85	VP1176	Samples
SN75HVD1176D	OBSOLETE	SOIC	D	8		TBD	Call TI	Call TI	0 to 70	VN1176	
SN75HVD1176DR	OBSOLETE	SOIC	D	8		TBD	Call TI	Call TI	0 to 70	VN1176	

(1) The marketing status values are defined as follows:

**ACTIVE:** Product device recommended for new designs.

**LIFEBUY:** TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

**NRND:** Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

**PREVIEW:** Device has been announced but is not in production. Samples may or may not be available.

**OBSOLETE:** TI has discontinued the production of the device.

(2) **RoHS:** TI defines "RoHS" to mean semiconductor products that are compliant with the current EU RoHS requirements for all 10 RoHS substances, including the requirement that RoHS substance do not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, "RoHS" products are suitable for use in specified lead-free processes. TI may reference these types of products as "Pb-Free".

**RoHS Exempt:** TI defines "RoHS Exempt" to mean products that contain lead but are compliant with EU RoHS pursuant to a specific EU RoHS exemption.

**Green:** TI defines "Green" to mean the content of Chlorine (Cl) and Bromine (Br) based flame retardants meet JS709B low halogen requirements of <=1000ppm threshold. Antimony trioxide based flame retardants must also meet the <=1000ppm threshold requirement.

(3) MSL, Peak Temp. - The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.

(4) There may be additional marking, which relates to the logo, the lot trace code information, or the environmental category on the device.

(5) Multiple Device Markings will be inside parentheses. Only one Device Marking contained in parentheses and separated by a "~" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Device Marking for that device.

(6) Lead finish/Ball material - Orderable Devices may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.

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**TAPE AND REEL INFORMATION**

**QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE**


\*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
SN65HVD1176DR	SOIC	D	8	2500	330.0	12.4	6.4	5.2	2.1	8.0	12.0	Q1
SN65HVD1176DR	SOIC	D	8	2500	330.0	12.4	6.4	5.2	2.1	8.0	12.0	Q1

**TAPE AND REEL BOX DIMENSIONS**


\*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
SN65HVD1176DR	SOIC	D	8	2500	356.0	356.0	35.0
SN65HVD1176DR	SOIC	D	8	2500	353.0	353.0	32.0



D0008A

# PACKAGE OUTLINE

SOIC - 1.75 mm max height

SMALL OUTLINE INTEGRATED CIRCUIT



4214825/C 02/2019

### NOTES:

- Linear dimensions are in inches [millimeters]. Dimensions in parenthesis are for reference only. Controlling dimensions are in inches. Dimensioning and tolerancing per ASME Y14.5M.
- This drawing is subject to change without notice.
- This dimension does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not exceed  $.006$  [0.15] per side.
- This dimension does not include interlead flash.
- Reference JEDEC registration MS-012, variation AA.

# EXAMPLE BOARD LAYOUT

D0008A

SOIC - 1.75 mm max height

SMALL OUTLINE INTEGRATED CIRCUIT



LAND PATTERN EXAMPLE  
 EXPOSED METAL SHOWN  
 SCALE:8X



SOLDER MASK DETAILS

4214825/C 02/2019

NOTES: (continued)

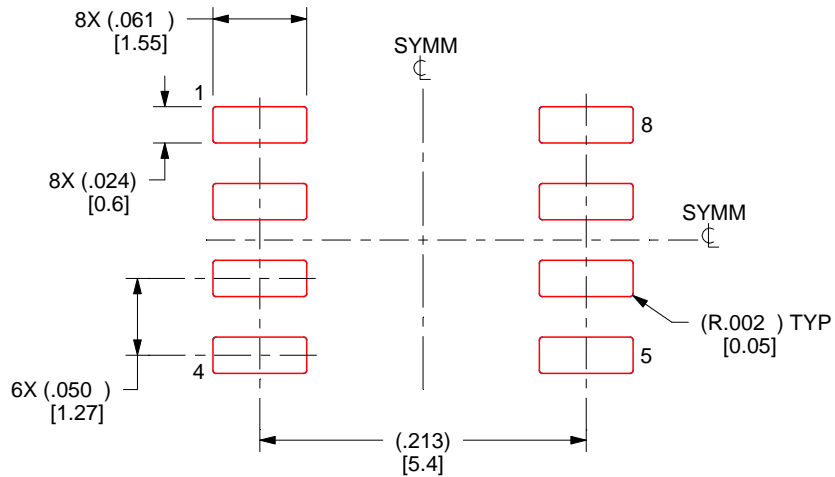
- 6. Publication IPC-7351 may have alternate designs.
- 7. Solder mask tolerances between and around signal pads can vary based on board fabrication site.

# EXAMPLE STENCIL DESIGN

D0008A

SOIC - 1.75 mm max height

SMALL OUTLINE INTEGRATED CIRCUIT



SOLDER PASTE EXAMPLE  
BASED ON .005 INCH [0.125 MM] THICK STENCIL  
SCALE:8X

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NOTES: (continued)

8. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
9. Board assembly site may have different recommendations for stencil design.

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郵送先住所 : Texas Instruments, Post Office Box 655303, Dallas, Texas 75265  
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